

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/712,706	ROOT ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	U	David E. Root, John Wood, and Nick Tufillaro; "New Techniques for Non-Linear Behavioral Modeling of Microwave/RD ICs from Simulation and Nonlinear Microwave Measurements"; June 2003; ACM; Proceedings of the 40th conference on Design Automation; pages 85-90
	V	John Wood and David E. Root; "The Behavioral Modeling of Microwave/RF ICs using Nonlinear Time Series Analysis"; June 2003; IEEE; pages 791-794
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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